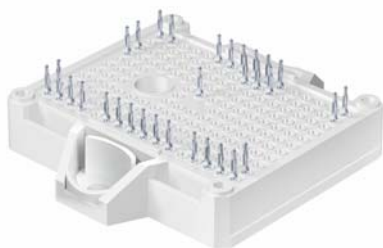


# SK200TMLI12F4TE2



SEMITOP®E2

## 3-Level TNPC

### SK200TMLI12F4TE2

#### Features\*

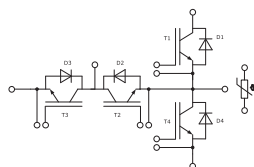
- Optimized design for superior thermal performances
- Low inductive design
- Press-Fit contact technology
- 1200V Trench IGBT4 Fast (F4)
- 650V Trench IGBT3 (E3)
- Robust and soft switching CAL4F diode technology
- Integrated NTC temperature sensor
- UL recognized file no. E 63 532

#### Typical Applications

- UPS
- Solar

#### Remarks\*

- Recommended  $T_{jop} = -40 \dots +150^\circ\text{C}$
- IGBT1: outer IGBTs T1 & T4
- IGBT2: inner IGBTs T2 & T3
- Diode1: outer diodes D1 & D4
- Diode2: inner diodes D2 & D3



TMLI-T

Absolute Maximum Ratings				
Symbol	Conditions	Values	Unit	
<b>IGBT1</b>				
$V_{CES}$	$T_j = 25^\circ\text{C}$	1200	V	
$I_C$	$\lambda_{paste}=0.8 \text{ W/(mK)}$	$T_s = 25^\circ\text{C}$	169	A
	$T_j = 175^\circ\text{C}$	$T_s = 70^\circ\text{C}$	135	A
$I_C$	$\lambda_{paste}=2.5 \text{ W/(mK)}$	$T_s = 25^\circ\text{C}$	248	A
	$T_j = 175^\circ\text{C}$	$T_s = 70^\circ\text{C}$	200	A
$I_{Cnom}$		200	A	
$I_{CRM}$		600	A	
$V_{GES}$		-20 ... 20	V	
$t_{psc}$	$V_{CC} = 800 \text{ V}, V_{GE} \leq 15 \text{ V}, T_j = 150^\circ\text{C}, V_{CES} \leq 1200 \text{ V}$	6	$\mu\text{s}$	
$T_j$		-40 ... 175	$^\circ\text{C}$	
<b>IGBT2</b>				
$V_{CES}$	$T_j = 25^\circ\text{C}$	650	V	
$I_C$	$\lambda_{paste}=0.8 \text{ W/(mK)}$	$T_s = 25^\circ\text{C}$	102	A
	$T_j = 175^\circ\text{C}$	$T_s = 70^\circ\text{C}$	81	A
$I_C$	$\lambda_{paste}=2.5 \text{ W/(mK)}$	$T_s = 25^\circ\text{C}$	123	A
	$T_j = 175^\circ\text{C}$	$T_s = 70^\circ\text{C}$	99	A
$I_{Cnom}$		100	A	
$I_{CRM}$		300	A	
$V_{GES}$		-20 ... 20	V	
$t_{psc}$	$V_{CC} = 360 \text{ V}, V_{GE} \leq 15 \text{ V}, T_j = 150^\circ\text{C}, V_{CES} \leq 650 \text{ V}$	6	$\mu\text{s}$	
$T_j$		-40 ... 175	$^\circ\text{C}$	
<b>Diode1</b>				
$V_{RRM}$	$T_j = 25^\circ\text{C}$	1200	V	
$I_F$	$\lambda_{paste}=0.8 \text{ W/(mK)}$	$T_s = 25^\circ\text{C}$	69	A
	$T_j = 175^\circ\text{C}$	$T_s = 70^\circ\text{C}$	55	A
$I_F$	$\lambda_{paste}=2.5 \text{ W/(mK)}$	$T_s = 25^\circ\text{C}$	101	A
	$T_j = 175^\circ\text{C}$	$T_s = 70^\circ\text{C}$	81	A
$I_{FRM}$		150	A	
$I_{FSM}$	10 ms, sin 180°, $T_j = 25^\circ\text{C}$	430	A	
$T_j$		-40 ... 175	$^\circ\text{C}$	
<b>Diode2</b>				
$V_{RRM}$	$T_j = 25^\circ\text{C}$	650	V	
$I_F$	$\lambda_{paste}=0.8 \text{ W/(mK)}$	$T_s = 25^\circ\text{C}$	98	A
	$T_j = 175^\circ\text{C}$	$T_s = 70^\circ\text{C}$	76	A
$I_F$	$\lambda_{paste}=2.5 \text{ W/(mK)}$	$T_s = 25^\circ\text{C}$	132	A
	$T_j = 175^\circ\text{C}$	$T_s = 70^\circ\text{C}$	104	A
$I_{FRM}$		200	A	
$I_{FSM}$	10 ms, sin 180°, $T_j = 25^\circ\text{C}$	820	A	
$T_j$		-40 ... 175	$^\circ\text{C}$	
<b>Module</b>				
$I_{t(RMS)}$		30	A	
$T_{stg}$		-40 ... 125	$^\circ\text{C}$	
$V_{isol}$	AC, sinusoidal, t = 1 min	2500	V	

# SK200TMLI12F4TE2



SEMITOP®E2

## 3-Level TNPC

### SK200TMLI12F4TE2

#### Features\*

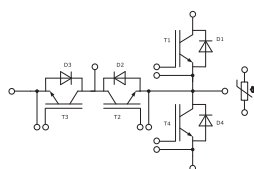
- Optimized design for superior thermal performances
- Low inductive design
- Press-Fit contact technology
- 1200V Trench IGBT4 Fast (F4)
- 650V Trench IGBT3 (E3)
- Robust and soft switching CAL4F diode technology
- Integrated NTC temperature sensor
- UL recognized file no. E 63 532

#### Typical Applications

- UPS
- Solar

#### Remarks\*

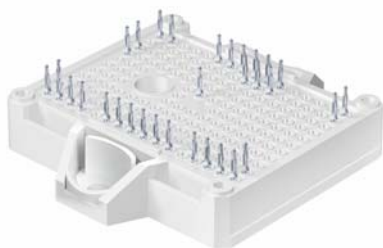
- Recommended  $T_{jop} = -40 \dots +150^\circ\text{C}$
- IGBT1: outer IGBTs T1 & T4
- IGBT2: inner IGBTs T2 & T3
- Diode1: outer diodes D1 & D4
- Diode2: inner diodes D2 & D3



TMLI-T

Characteristics						
Symbol	Conditions		min.	typ.	max.	Unit
<b>IGBT1</b>						
$V_{CE(sat)}$	$I_C = 200\text{ A}$ $V_{GE} = 15\text{ V}$ chipllevel	$T_j = 25^\circ\text{C}$		2.05	2.42	V
		$T_j = 150^\circ\text{C}$		2.59	2.96	V
$V_{CE0}$	chipllevel	$T_j = 25^\circ\text{C}$		1.10	1.28	V
		$T_j = 150^\circ\text{C}$		0.95	1.13	V
$r_{CE}$	$V_{GE} = 15\text{ V}$ chipllevel	$T_j = 25^\circ\text{C}$		4.8	5.7	m $\Omega$
		$T_j = 150^\circ\text{C}$		8.2	9.2	m $\Omega$
$V_{GE(th)}$	$V_{GE} = V_{CE}, I_C = 7.6\text{ mA}$		5.2	5.8	6.4	V
$I_{CES}$	$V_{GE} = 0\text{ V}, V_{CE} = 1200\text{ V}, T_j = 25^\circ\text{C}$				2.67	mA
$C_{ies}$	$V_{CE} = 25\text{ V}$ $V_{GE} = 0\text{ V}$	$f = 1\text{ MHz}$		12.3		nF
$C_{oes}$		$f = 1\text{ MHz}$		0.81		nF
$C_{res}$		$f = 1\text{ MHz}$		0.69		nF
$Q_G$	$V_{GE} = -15\text{ V} \dots +15\text{ V}$			1400		nC
$R_{Gint}$	$T_j = 25^\circ\text{C}$			3.8		$\Omega$
$t_{d(on)}$	$V_{CE} = 400\text{ V}$ $I_C = 100\text{ A}$	$T_j = 150^\circ\text{C}$		164		ns
$t_r$	$V_{GE} = +15/-15\text{ V}$	$T_j = 150^\circ\text{C}$		30		ns
$E_{on}$	$R_{G on} = 1.1\ \Omega$	$T_j = 150^\circ\text{C}$		4.44		mJ
$t_{d(off)}$	$R_{G off} = 1.1\ \Omega$	$T_j = 150^\circ\text{C}$		404		ns
$t_f$	$di/dt_{on} = 4708\text{ A}/\mu\text{s}$	$T_j = 150^\circ\text{C}$		58		ns
$E_{off}$		$T_j = 150^\circ\text{C}$		5.4		mJ
$R_{th(j-s)}$	per IGBT, $\lambda_{paste} = 0.8\text{ W}/(\text{mK})$			0.32		K/W
$R_{th(j-s)}$	per IGBT, $\lambda_{paste} = 2.5\text{ W}/(\text{mK})$			0.17		K/W
<b>IGBT2</b>						
$V_{CE(sat)}$	$I_C = 100\text{ A}$ $V_{GE} = 15\text{ V}$ chipllevel	$T_j = 25^\circ\text{C}$		1.45	1.85	V
		$T_j = 150^\circ\text{C}$		1.70	2.10	V
$V_{CE0}$	chipllevel	$T_j = 25^\circ\text{C}$		0.90	1.00	V
		$T_j = 150^\circ\text{C}$		0.82	0.90	V
$r_{CE}$	$V_{GE} = 15\text{ V}$ chipllevel	$T_j = 25^\circ\text{C}$		5.5	8.5	m $\Omega$
		$T_j = 150^\circ\text{C}$		8.8	12	m $\Omega$
$V_{GE(th)}$	$V_{GE} = V_{CE}, I_C = 1.6\text{ mA}$		5	5.8	6.5	V
$I_{CES}$	$V_{GE} = 0\text{ V}, V_{CE} = 650\text{ V}, T_j = 25^\circ\text{C}$				0.29	mA
$C_{ies}$	$V_{CE} = 25\text{ V}$ $V_{GE} = 0\text{ V}$	$f = 1\text{ MHz}$		6.16		nF
$C_{oes}$		$f = 1\text{ MHz}$		0.384		nF
$C_{res}$		$f = 1\text{ MHz}$		0.183		nF
$Q_G$	$V_{GE} = -15\text{ V} \dots +15\text{ V}$			1000		nC
$R_{Gint}$	$T_j = 25^\circ\text{C}$			2.0		$\Omega$
$t_{d(on)}$	$V_{CE} = 400\text{ V}$ $I_C = 100\text{ A}$	$T_j = 150^\circ\text{C}$		78		ns
$t_r$	$V_{GE} = +15/-15\text{ V}$	$T_j = 150^\circ\text{C}$		31		ns
$E_{on}$	$R_{G on} = 3.3\ \Omega$	$T_j = 150^\circ\text{C}$		4.3		mJ
$t_{d(off)}$	$R_{G off} = 3.3\ \Omega$	$T_j = 150^\circ\text{C}$		262		ns
$t_f$	$di/dt_{on} = 3800\text{ A}/\mu\text{s}$	$T_j = 150^\circ\text{C}$		52		ns
$E_{off}$		$T_j = 150^\circ\text{C}$		4.5		mJ
$R_{th(j-s)}$	per IGBT, $\lambda_{paste} = 0.8\text{ W}/(\text{mK})$			0.67		K/W
$R_{th(j-s)}$	per IGBT, $\lambda_{paste} = 2.5\text{ W}/(\text{mK})$			0.49		K/W

# SK200TMLI12F4TE2



SEMITOP®E2

## 3-Level TNPC

### SK200TMLI12F4TE2

#### Features\*

- Optimized design for superior thermal performances
- Low inductive design
- Press-Fit contact technology
- 1200V Trench IGBT4 Fast (F4)
- 650V Trench IGBT3 (E3)
- Robust and soft switching CAL4F diode technology
- Integrated NTC temperature sensor
- UL recognized file no. E 63 532

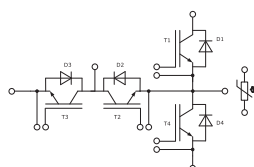
#### Typical Applications

- UPS
- Solar

#### Remarks\*

- Recommended  $T_{jop} = -40 \dots +150^{\circ}\text{C}$
- IGBT1: outer IGBTs T1 & T4
- IGBT2: inner IGBTs T2 & T3
- Diode1: outer diodes D1 & D4
- Diode2: inner diodes D2 & D3

Characteristics						
Symbol	Conditions		min.	typ.	max.	Unit
<b>Diode1</b>						
$V_F = V_{EC}$	$I_F = 75 \text{ A}$	$T_j = 25^{\circ}\text{C}$		2.17	2.49	V
		chipelevel	$T_j = 150^{\circ}\text{C}$	2.11	2.42	V
$V_{F0}$	chipelevel	$T_j = 25^{\circ}\text{C}$		1.30	1.50	V
		$T_j = 150^{\circ}\text{C}$		0.90	1.10	V
$r_F$	chipelevel	$T_j = 25^{\circ}\text{C}$		12	13	m $\Omega$
		$T_j = 150^{\circ}\text{C}$		16	18	m $\Omega$
$I_{RRM}$	$I_F = 100 \text{ A}$	$T_j = 150^{\circ}\text{C}$		120		A
$Q_{rr}$	$di/dt_{off} = 3800 \text{ A}/\mu\text{s}$ $V_R = 400 \text{ V}$	$T_j = 150^{\circ}\text{C}$		12.3		$\mu\text{C}$
$E_{rr}$	$V_{GE} = +15/-15 \text{ V}$	$T_j = 150^{\circ}\text{C}$		3.2		mJ
$R_{th(j-s)}$	per Diode, $\lambda_{paste}=0.8 \text{ W}/(\text{mK})$			1.01		K/W
$R_{th(j-s)}$	per Diode, $\lambda_{paste}=2.5 \text{ W}/(\text{mK})$			0.55		K/W
<b>Diode2</b>						
$V_F = V_{EC}$	$I_F = 100 \text{ A}$	$T_j = 25^{\circ}\text{C}$		1.40	1.76	V
		chipelevel	$T_j = 150^{\circ}\text{C}$	1.38	1.77	V
$V_{F0}$	chipelevel	$T_j = 25^{\circ}\text{C}$		1.04	1.24	V
		$T_j = 150^{\circ}\text{C}$		0.85	0.99	V
$r_F$	chipelevel	$T_j = 25^{\circ}\text{C}$		3.6	5.3	m $\Omega$
		$T_j = 150^{\circ}\text{C}$		5.3	7.8	m $\Omega$
$I_{RRM}$	$I_F = 100 \text{ A}$	$T_j = 150^{\circ}\text{C}$		151		A
$Q_{rr}$	$di/dt_{off} = 4823 \text{ A}/\mu\text{s}$ $V_R = 400 \text{ V}$	$T_j = 150^{\circ}\text{C}$		12.2		$\mu\text{C}$
$E_{rr}$	$V_{GE} = +15/-15 \text{ V}$	$T_j = 150^{\circ}\text{C}$		3.14		mJ
$R_{th(j-s)}$	per Diode, $\lambda_{paste}=0.8 \text{ W}/(\text{mK})$			0.91		K/W
$R_{th(j-s)}$	per Diode, $\lambda_{paste}=2.5 \text{ W}/(\text{mK})$			0.59		K/W
<b>Module</b>						
$L_{sCE1}$				14		nH
$L_{CE}$				-		nH
$R_{CC'+EE'}$	per switch	$T_s = 25^{\circ}\text{C}$		-		m $\Omega$
		$T_s = 150^{\circ}\text{C}$		-		m $\Omega$
$M_s$	to heatsink		1.6		2.3	Nm
$M_t$				-		Nm
						Nm
w				35		g
<b>Temperature Sensor</b>						
$R_{100}$	$T_c=100^{\circ}\text{C}$ ( $R_{25}=5 \text{ k}\Omega$ )			$493 \pm 5\%$		$\Omega$
$B_{100/125}$	$R(T)=R_{100}\exp[B_{100/125}(1/T-1/T_{100})]$ ; T[K];			$3550 \pm 2\%$		K



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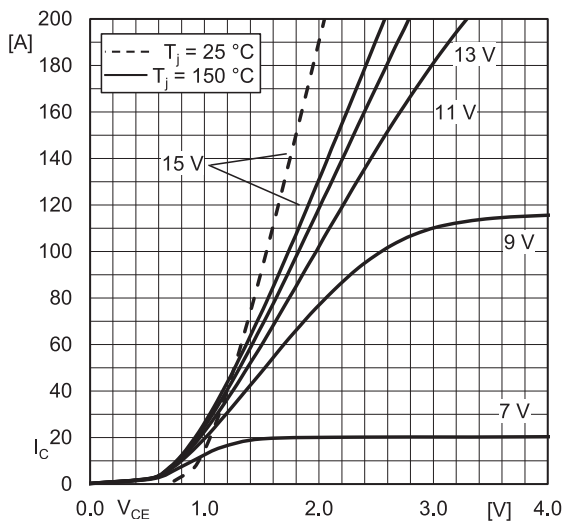


Fig. 1: Typ. IGBT1 output characteristic, incl.  $R_{CC'+EE'}$

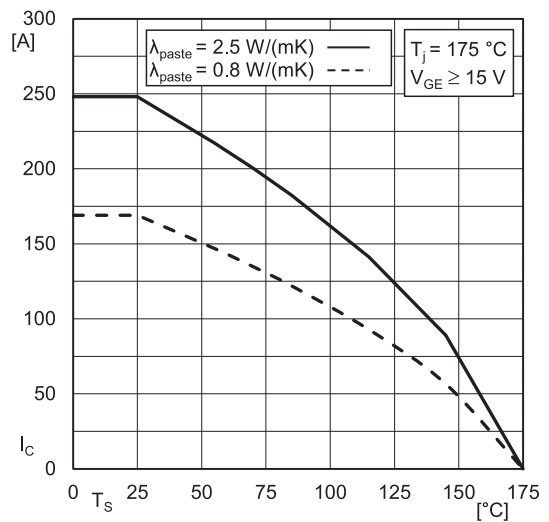


Fig. 2: IGBT1 rated current vs. Temperature  $I_C=f(T_s)$

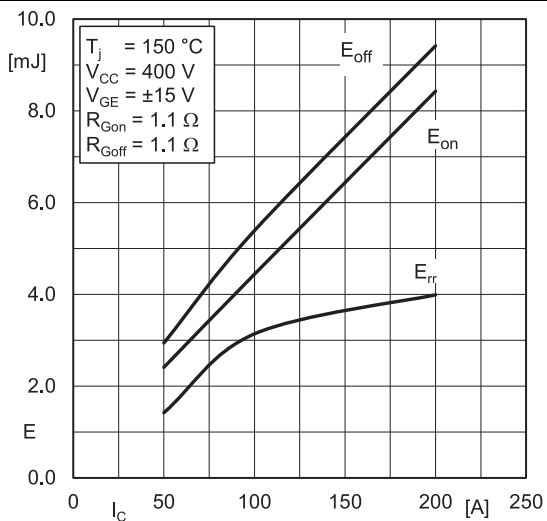


Fig. 3: Typ. IGBT1 & Diode2 turn-on /-off energy =  $f(I_C)$

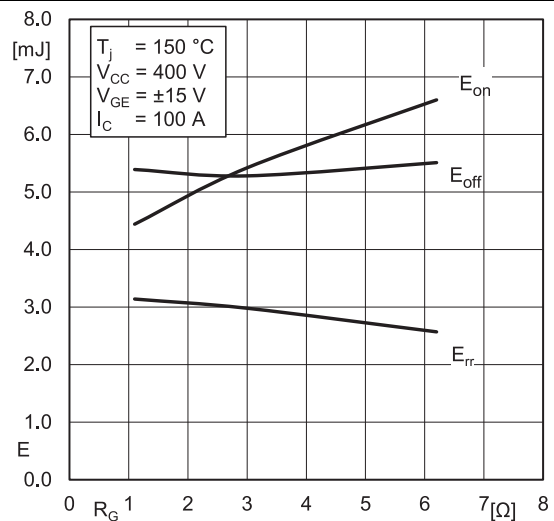


Fig. 4: Typ. IGBT1 & Diode2 turn-on /-off energy =  $f(R_G)$

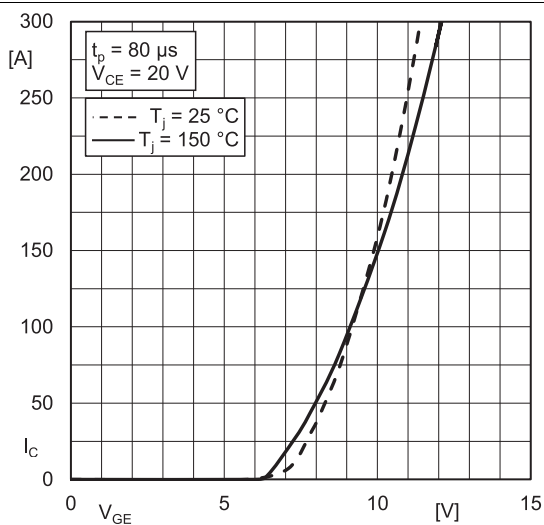


Fig. 5: Typ. IGBT1 transfer characteristic

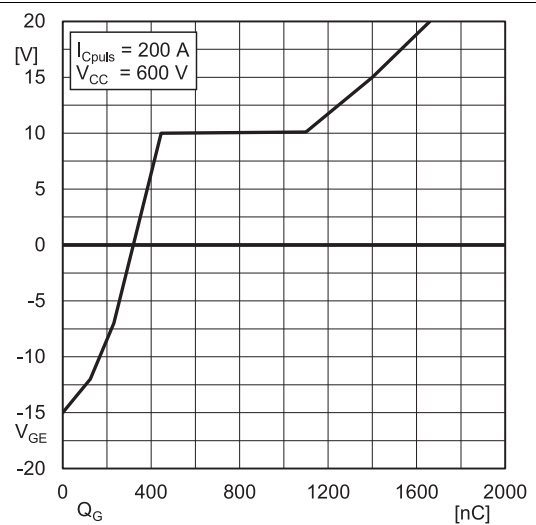


Fig. 6: Typ. IGBT1 gate charge characteristic

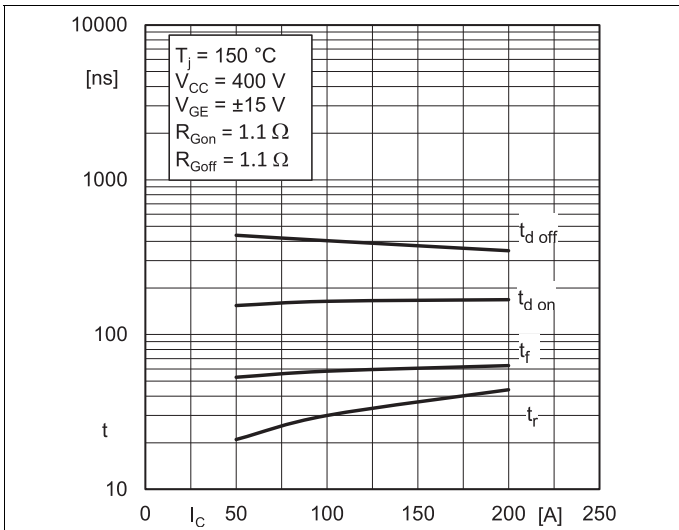


Fig. 7: Typ. IGBT1 switching times vs.  $I_C$

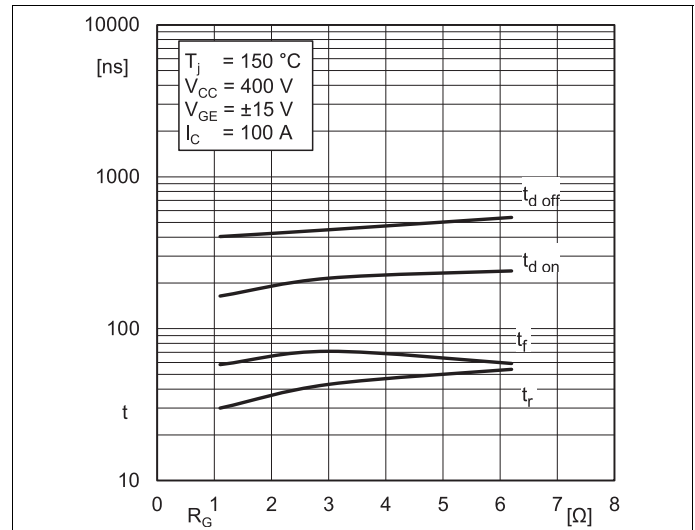


Fig. 8: Typ. IGBT1 switching times vs. gate resistor  $R_G$

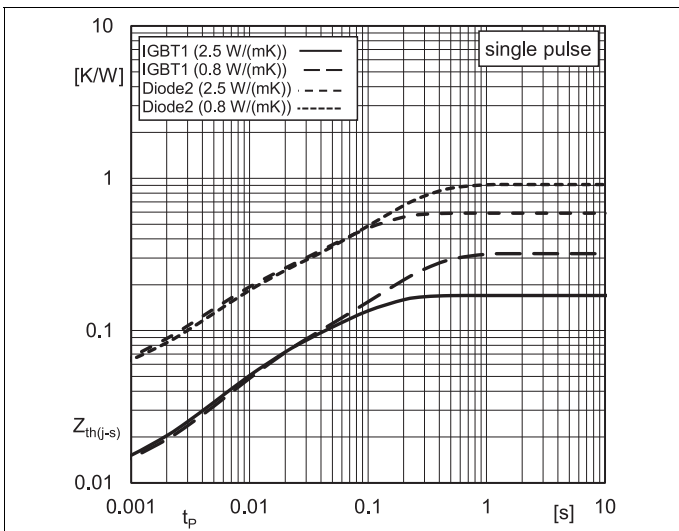


Fig. 9: Transient thermal impedance of IGBT1 & Diode2

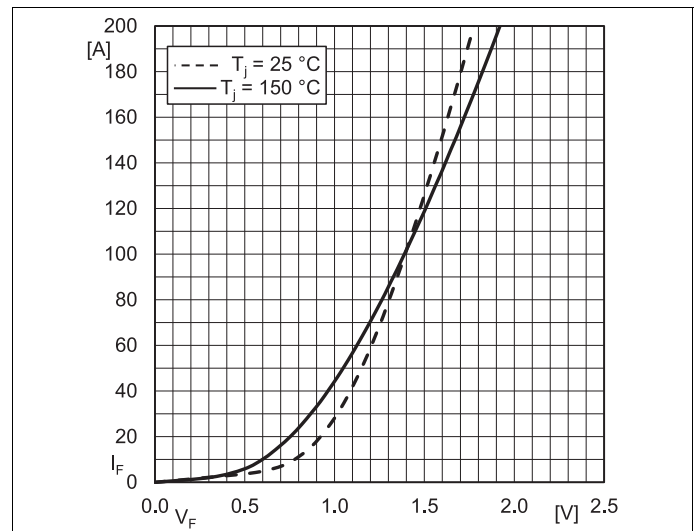


Fig. 10: Typ. Diode2 forward characteristic, incl.  $R_{CC+EE'}$

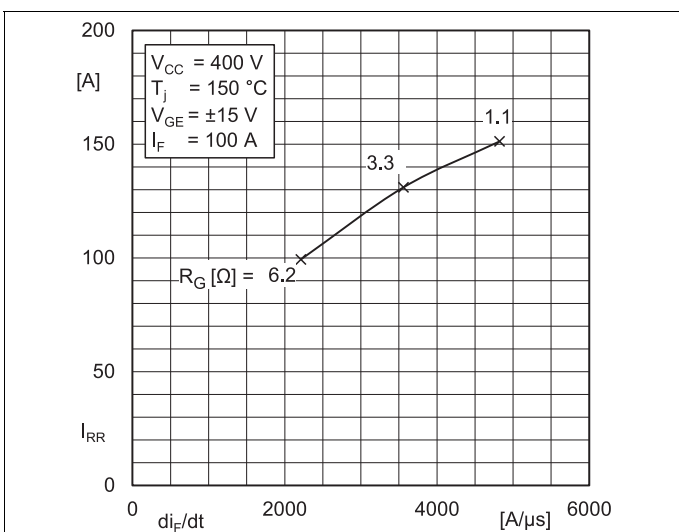


Fig. 11: Typ. Diode2 peak reverse recovery current

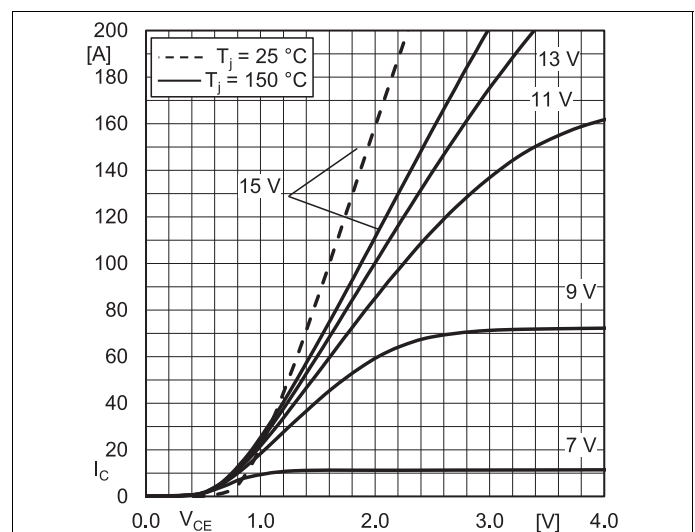


Fig. 13: Typ. IGBT2 output characteristic, incl.  $R_{CC+EE'}$

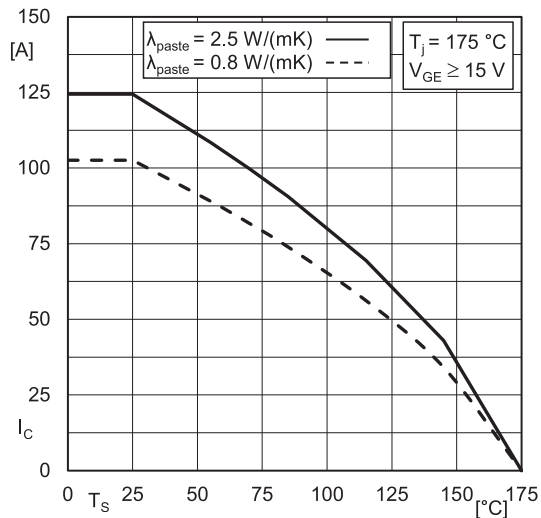


Fig. 14: IGBT2 Rated current vs. Temperature  $I_c = f(T_s)$

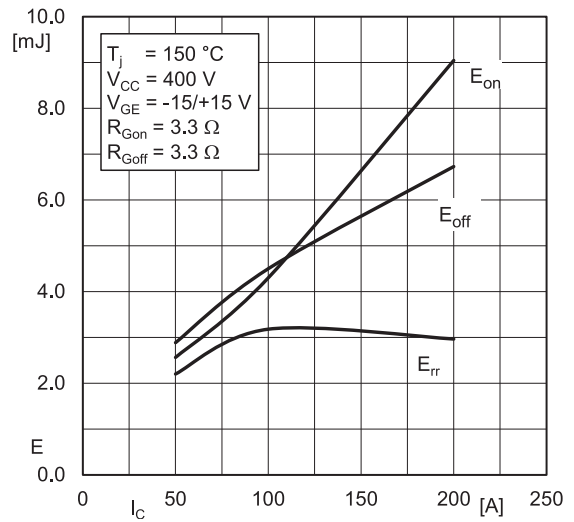


Fig. 15: Typ. IGBT2 & Diode1 turn-on /-off energy =  $f(I_c)$

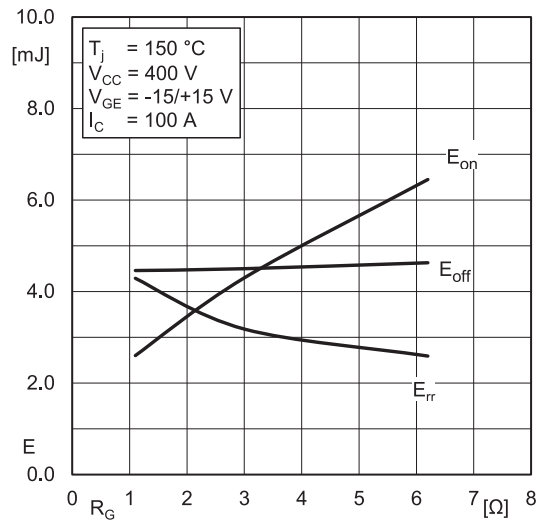


Fig. 16: Typ. IGBT2 & Diode1 turn-on /-off energy =  $f(R_G)$

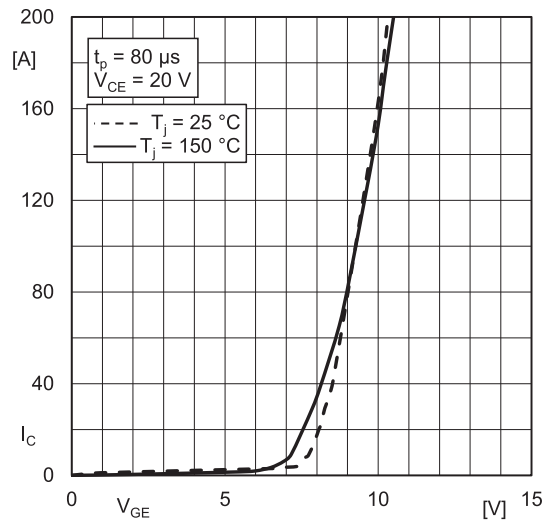


Fig. 17: Typ. IGBT2 transfer characteristic

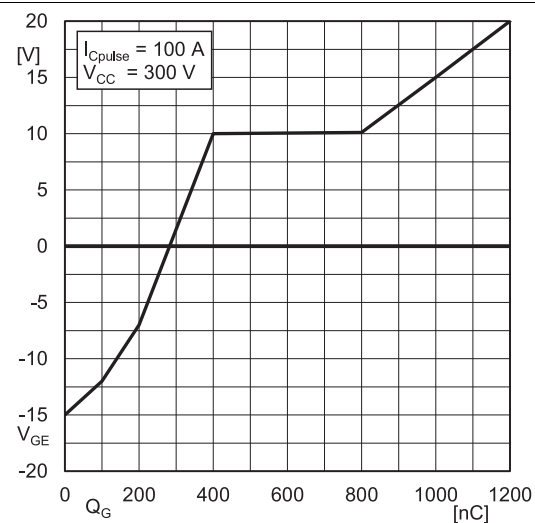


Fig. 18: Typ. IGBT2 gate charge characteristic

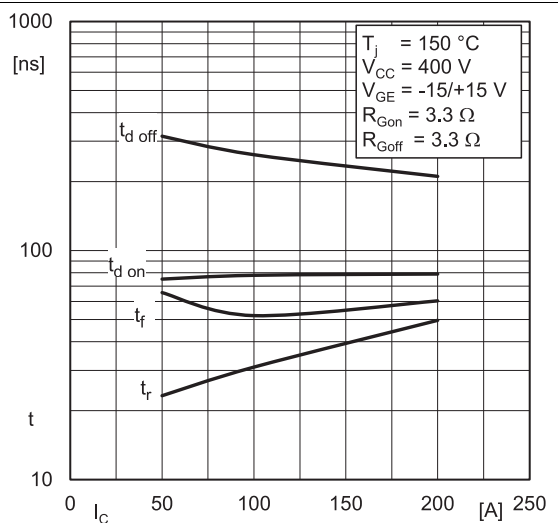


Fig. 19: Typ. IGBT2 switching times vs.  $I_c$

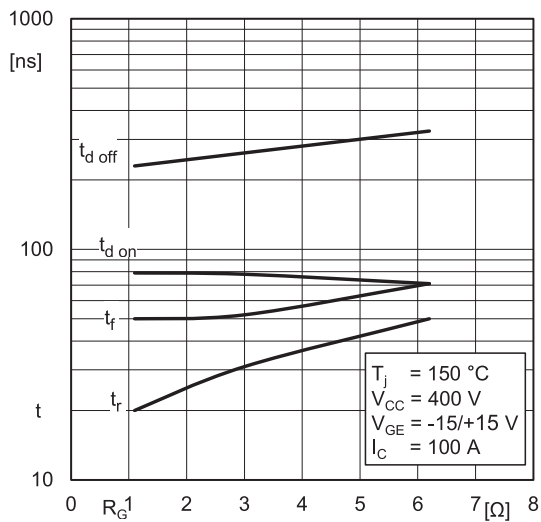


Fig. 20: Typ. IGBT2 switching times vs. gate resistor  $R_G$

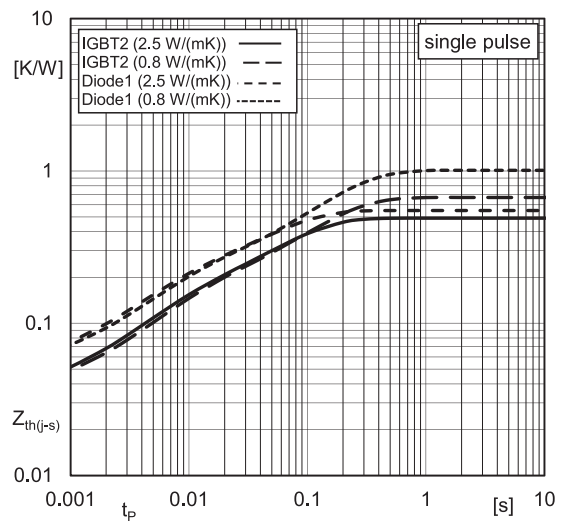


Fig. 21: Transient thermal impedance of IGBT2 & Diode1

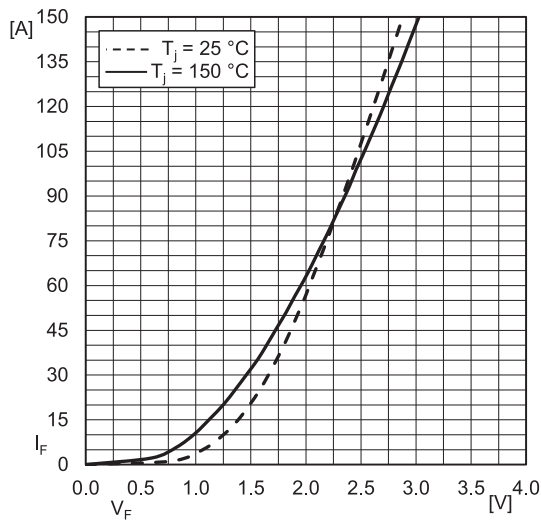


Fig. 22: Typ. Diode1 forward characteristic, incl.  $R_{CC+EE}$

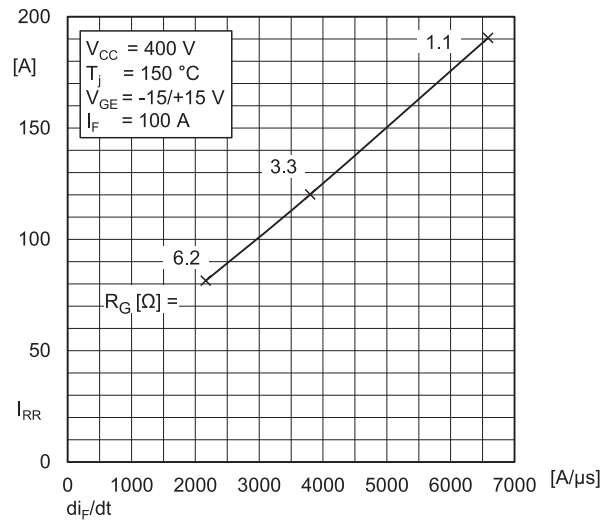


Fig. 23: Typ. Diode1 peak reverse recovery current

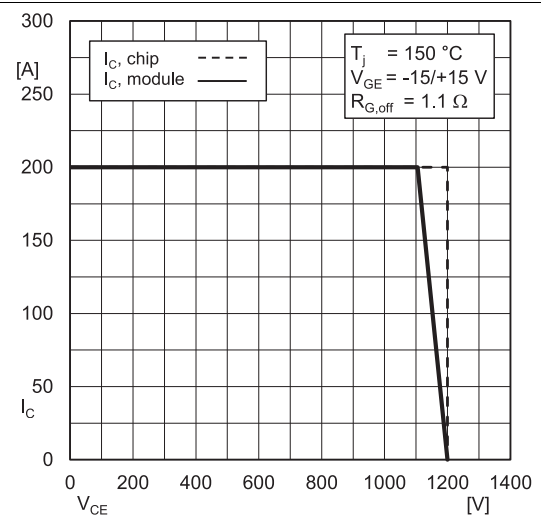


Fig. 25: RBSOA IGBT1

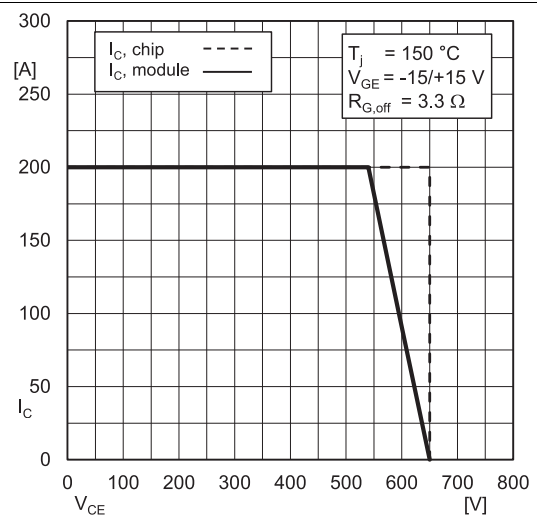
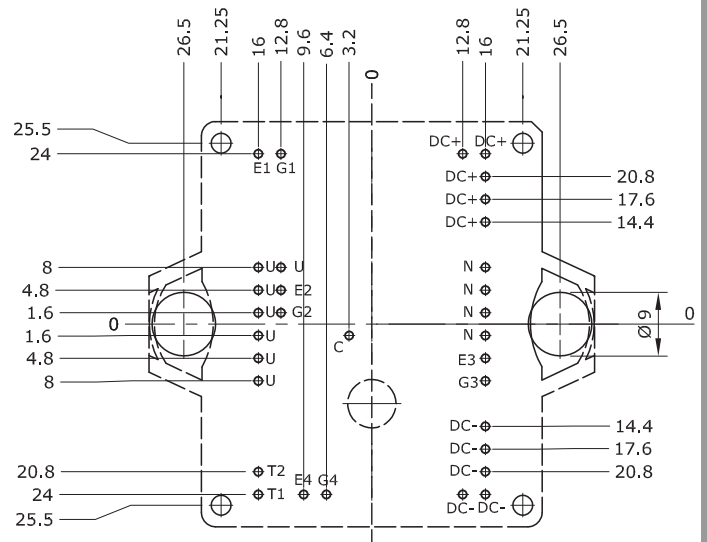
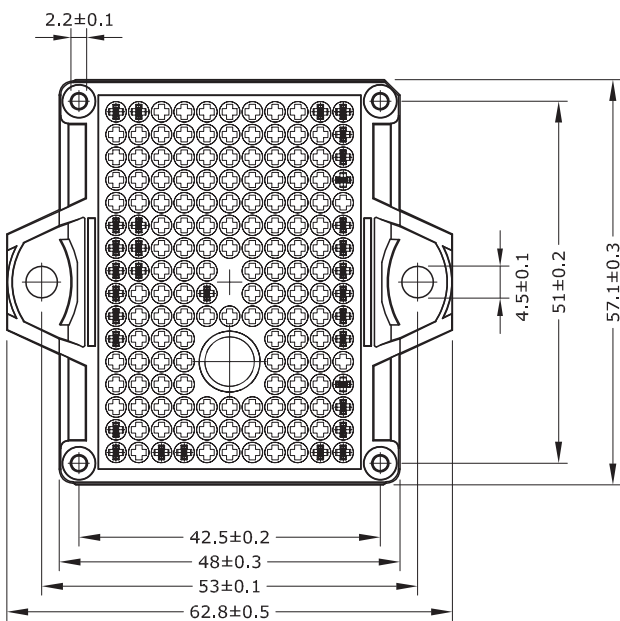
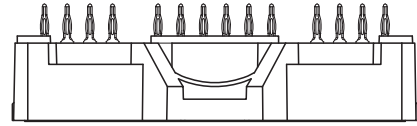
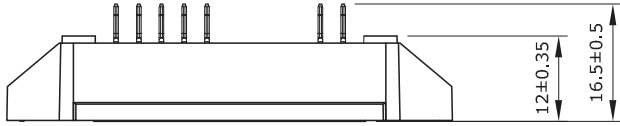


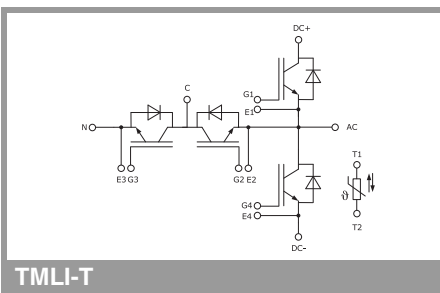
Fig. 26: RBSOA IGBT2

# SK200TMLI12F4TE2



- Pin-Grid 3.2 mm
- Tolerance of PCB hole pattern  $\boxed{\oplus|\ominus|\varnothing 0.1}$
- Diameters of drill  $\varnothing 1.15\text{mm}$
- Copper thickness in hole 25 - 50  $\mu\text{m}$
- Hole specification for contacts:  
refer to SEMITOP E1/E2 Mounting Instruction

SEMITOP®E2



TMLI-T



This is an electrostatic discharge sensitive device (ESDS) due to international standard IEC 61340.

## **\*IMPORTANT INFORMATION AND WARNINGS**

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